

EAST Search History**EAST Search History (Prior Art)**

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	720	(@ad<"20030818" or @rlad<"20030818") and 257/369.cds. and (thermal expansion coefficient)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/12 13:26
S19	30	(@ad<"20030818" or @rlad<"20030818") and 257/E29.298.cds. and (stress strain mobility) and coefficient	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/12 12:41
S18	45	("3562608" "3829881" "4177084" "4198649" "4385937" "4418470" "4425700" "4463492" "4509990" "4523963" "4588447" "4607176" "4615762" "4617066" "4659392" "4766482" "4775641" "4843448" "5027171" "5141882" "5229644" "5294823" "5300443" "5572040").PN. OR ("5883396").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2010/11/12 12:39
S17	29	(@ad<"20030818" or @rlad<"20030818") and 257/369.cds. and (stress strain mobility) and coefficient	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/12 12:10
S12	180	(@ad<"20030818" or @rlad<"20030818") and 257/369.cds. and (stress strain tensile compressive gpa)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/11 11:45
S11	2096	(@ad<"20030818" or @rlad<"20030818") and 257/369.cds.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/11 11:44

S10	266	(@ad<"20030818" or @rlad<"20030818") and 438/285.ccls.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/11 10:50
S9	146	(@ad<"20030818" or @rlad<"20030818") and 438/938.ccls.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/11 10:08
S8	284	(@ad<"20030818" or @rlad<"20030818") and 257/E29.298.ccls.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 15:36
S7	168	(@ad<"20030818" or @rlad<"20030818") and (stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient expansion) same (cause increase change)) and (stress strain tensile compressive mobility).ab.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:46
S6	676	(@ad<"20030818" or @rlad<"20030818") and (stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient expansion) same (cause increase change))	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:43
S5	364	(@ad<"20030818" or @rlad<"20030818") and (stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient) same (cause increase change))	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:43

S4	5	(@ad<"20030818" or @rlad<"20030818") and (stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient) same (cause increase change)). clm.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:42
S3	13	(stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient) same (cause increase change)). clm.	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:19
S2	744	(stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient) same (cause increase change))	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:19
S1	1015	(stress strain) and mobility and (transistor fet mos mosfet pfet nfet pmos nmos) and ((stress strain) same (coefficient expansion) same (cause increase change))	US_PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2010/11/10 14:19

EAST Search History (Interference)

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S16	148	((stress strain mobility tensile compressive compression) and (transistor fet mos mosfet pfet nfet pmos nmos) and (coefficient expansion thermal) and gate and substrate). clm.	USPAT; UPAD	OR	ON	2010/11/11 13:09
S15	124	257/369.ccls. and (stress strain tensile compressive mobility). clm.	USPAT; UPAD	OR	ON	2010/11/11 12:27
S14	453	257/369.ccls. and (stress strain tensile compressive mobility)	USPAT; UPAD	OR	ON	2010/11/11 12:26
S13	1527	257/369.ccls.	USPAT; UPAD	OR	ON	2010/11/11 12:26

11/12/2010 1:28:30 PM

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